



Microwave Dielectric Properties of CuO-V₂O₅-Bi₂O₃-Doped ZnNb₂O₆ Ceramics with Low Sintering Temperature

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Abstract. Microwave dielectric properties of low temperature sintering ZnNb₂O₆ ceramics doped with CuO-V₂O₅-Bi₂O₃ additions were investigated systematically. The co-doping of CuO, V₂O₅ and Bi₂O₃ can significantly lower the sintering temperature of ZnNb₂O₆ ceramics from 1150 to 870°C. The secondary phase containing Cu, V, Bi and Zn was observed at grain boundary junctions, and the amount of secondary phase increased with increasing CuO-V₂O₅-Bi₂O₃ content. The dielectric properties at microwave frequencies (7–9 GHz) in this system exhibited a significant dependence on the relative density, content of additives and microstructure of the ceramics. The dielectric constant (ϵ_r) of ZnNb₂O₆ ceramics increased from 21.95 to 24.18 with increasing CuO-V₂O₅-Bi₂O₃ additions from 1.5 to 4.0 wt%. The quality factors ($Q \times f$) of this system decreased with increasing CuO-V₂O₅-Bi₂O₃ content and ranged from 36118 to 67100 GHz for sintered ceramics, furthermore, all $Q \times f$ values of samples with CuO-V₂O₅-Bi₂O₃ additions are lower than that of un-doped ZnNb₂O₆ ceramics sintered at 1150°C for 2 h. The temperature coefficient of resonant frequency (τ_f) changed from -33.16 to -25.96 ppm/°C with increasing CuO-V₂O₅-Bi₂O₃ from 1.5 to 4.0 wt%.

Keywords: microwave dielectric ceramics, ZnNb₂O₆, low temperature sintering

Introduction

Niobium based, columbite-type compounds such as MNb₂O₆ (M = Zn, Mg, Ca, Mn, Cu and Co) have been investigated as microwave dielectric resonators by Maeda et al. [1] and Lee et al. [2, 3]. The evaluations of the microwave dielectric properties of these compounds reveal a high quality factor ($Q \times f$) and a high dielectric constant (ϵ_r). Among these compounds, ZnNb₂O₆ has excellent microwave dielectric properties: $Q \times f = 87300$ GHz, $\epsilon_r = 25$ and $\tau_f = -56$ ppm/°C [2, 3]. Moreover, its sintering temperature is only about 1150°C, which can be easily reduced to below 1000°C. Therefore, ZnNb₂O₆ ceramics are promising candidates for low-temperature sintering dielectrics applied in multilayer microwave devices.

CuO and CaF₂ have been used for sintering aids to lower the sintering of ZnNb₂O₆ ceramics by Lee et al. [4] and Zhang et al. [5]. However, too large amount of dopant would cause decrease of dielectric properties. The melting points of CuO, Bi₂O₃ and V₂O₅ are 1326, 825 and 678°C, respectively. These oxides have been introduced as sintering aids to create a liquid phase which lowers the sintering temperature and results in good dielectric properties [6, 7]. However, the effects of co-doping with more than two oxides on the sintering behavior of ZnNb₂O₆, have not been thoroughly investigated.

In this work, ZnNb₂O₆ was selected as the host materials, CuO, Bi₂O₃ and V₂O₅ were co-added as sintering aids to lower the sintering temperature of ZnNb₂O₆ ceramics. The effects of co-doping of CuO, Bi₂O₃ and V₂O₅ on the low temperature sintering, microstructure and microwave dielectric properties of ZnNb₂O₆ ceramics were investigated.

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Experimental Procedure

ZnNb₂O₆ powder was synthesized by the conventional mixed oxide method. High purity oxide powders (>99.99%) of ZnO and Nb₂O₅ were used as starting materials. They were mixed, according to the composition ZnNb₂O₆, and ball-milled in alcohol for 6 h. After drying, the product was calcined at 1000°C for 2 h. The ZnNb₂O₆ ceramic powder was mixed with 0.5 wt% CuO, 0.5 wt% V₂O₅ and 0.5–3 wt% Bi₂O₃ by ballmilling with alcohol for 2 h. The total amount of CuO, V₂O₅ and Bi₂O₃ ranged from 1.5 wt% to 4.0 wt%. After drying, the powder was pressed into pellets of 10 mm in diameter and 4 mm in thickness at 100 MPa. The pellets were sintered at 790–950°C for 2 h.

The crystalline phases of the sintered samples were analyzed by X-ray diffraction (XRD) using Cu K α radiation. The densities of the specimens were measured by Archimedes method. Polished and thermal etched surfaces of sintered samples were examined by using scanning electron microscopy (SEM) and transmission electron microscopy (TEM). The dielectric properties at microwave frequency (6–8 GHz) were measured with a HP8720ES network analyzer using Hakki-Coleman's dielectric resonator method, as modified and improved by Courtney and Kobayashi et al. [8–10].

Results and Discussions

The XRD patterns of ZnNb₂O₆ ceramics doped with CuO-V₂O₅-Bi₂O₃ sintered at 870°C for 2 h were shown in Fig. 1(a). ZnNb₂O₆ ceramics were single phase with a columbite structure when the total amount of CuO-V₂O₅-Bi₂O₃ less than 3.0 wt%. However, a second phase (marked as ‘*’) was detected in the samples with 3.0–4.0 wt% CuO-V₂O₅-Bi₂O₃ addition. In order to clarify the secondary phase, 10 wt% CuO-V₂O₅-Bi₂O₃ additions was added to ZnNb₂O₆ ceramics and sintered at 830°C. The XRD patterns were shown in Fig. 1(b). The strongest peak of the secondary phase was observed at 29.28°. However, the secondary phase was not identified in this study because that the reflection peak of the secondary phase was not match to any phase which may be a any combination of five elements including Cu, V, Bi, Zn and O according to EDS analysis results (Fig. 4(d) and (e)). Those results suggest that the secondary phase may be a new phase and has not

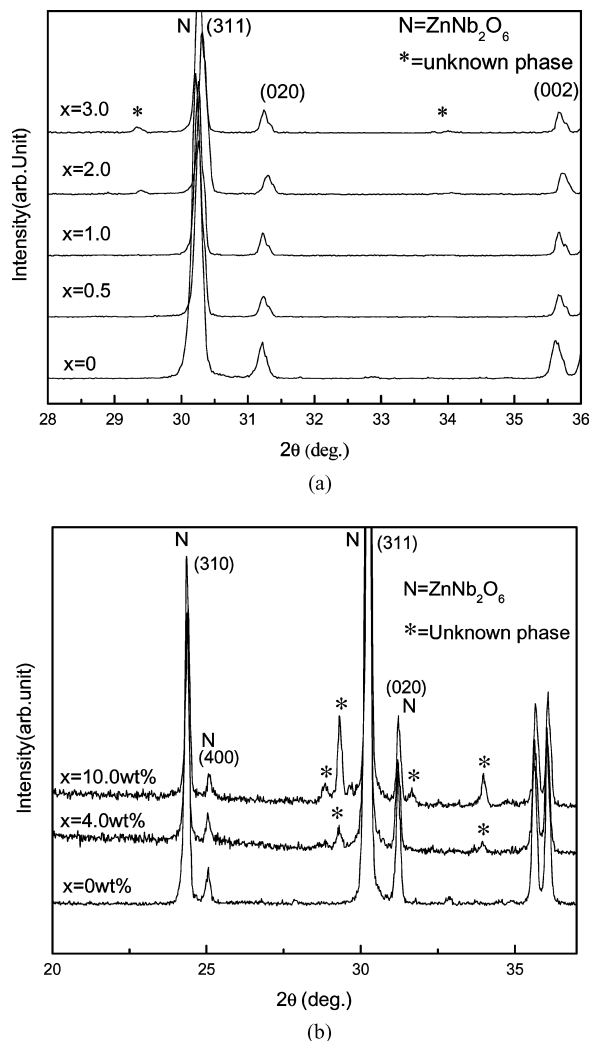


Fig. 1. The XRD patterns of ZnNb₂O₆ ceramics with 0.5 wt% CuO + 0.5 wt% V₂O₅ + (x) wt% Bi₂O₃ additions sintered at 870°C for 2 h. (b) The XRD patterns of ZnNb₂O₆ ceramics with (x) wt% CuO-V₂O₅-Bi₂O₃ additions sintered at 830°C for 2 h.

been reported before. Therefore, the secondary phase is needed to further study in later work.

The relative theoretical densities of ZnNb₂O₆ ceramics doped with CuO-V₂O₅-Bi₂O₃ as a function of sintering temperature were shown in Fig. 2. The densities of samples steadily increased with increasing sintering temperature, and saturated at 850–950°C. It was difficult to densify ZnNb₂O₆ ceramics when the sintering temperature is lower than 1150°C. However, the densification temperature of ZnNb₂O₆ ceramics decreased with increasing amount of CuO-V₂O₅-Bi₂O₃.

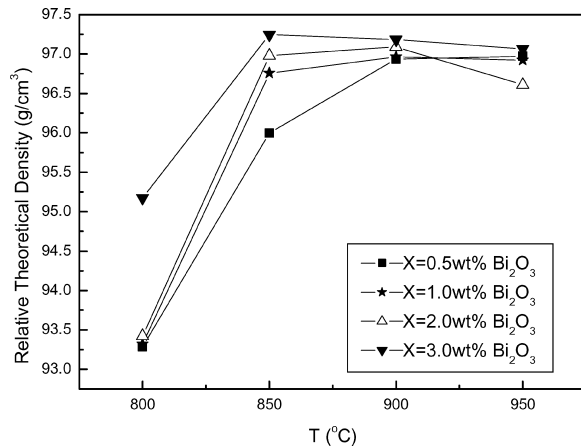


Fig. 2. The relative theoretical densities of ZnNb₂O₆ ceramics with 0.5 wt% CuO + 0.5 wt% V₂O₅ + (x) wt% Bi₂O₃ additions as a function of sintering temperature.

96% theoretical density could be obtained for all samples when the sintering temperature higher than 870°C. The results suggest that co-doping with CuO, V₂O₅ and Bi₂O₃ can significantly lower the sintering temperature of ZnNb₂O₆ ceramics from 1150 to 870°C.

Typical microstructure of polished and thermal etched ZnNb₂O₆ ceramics with CuO-V₂O₅-Bi₂O₃ are shown in Fig. 3. SEM micrographs show that the grain shape of un-doped ZnNb₂O₆ ceramics is equiaxed and uniform. The average grain size is ranged from 8 to 9 μm (Fig. 3(a)). However, the grain shape change to long column for samples doped with CuO-V₂O₅-Bi₂O₃, and the average grain size in major axis direction decreased with increasing amount of CuO-V₂O₅-Bi₂O₃ addition (Fig. 3(b), (c) and (d)). It is suggested that large amount of CuO-V₂O₅-Bi₂O₃ additives prevent the grain growth of samples.

Figure 4(a) and (b) shows bright-field images and a select-area diffraction pattern of ZnNb₂O₆ ceramics with 4.0 wt% CuO-V₂O₅-Bi₂O₃ sintered at 870°C for 2 h. A triangle intergranular phase (marked at 'a') is observed at the grain boundary junctions (Fig. 4(a)). The ring diffraction pattern of the intergranular phase indicates that it is composed of microcrystals (Fig. 4(b)). Figure 4(c) shows another bright-field images of ZnNb₂O₆ ceramics with 1.5 wt% CuO-V₂O₅-Bi₂O₃ addition sintered at 870°C. A triangle intergranular phase (marked at '2' and '3') is also observed at the grain boundary junctions. In order to clarify the compositions of intergranular phase, EDS results of the in-

Table 1. Chemical Composition of ZnNb₂O₆ ceramics with 4 wt% CuO-V₂O₅-Bi₂O₃ sintered at 870°C.

Marked region	Composition (mol%)				
	Zinc	Niobium	Copper	Bismuth	Vanadium
1	27.34	72.36	0.08	0.13	0.09
2	31.37	2.54	22.23	16.09	27.28
3	36.28	3.42	20.11	18.15	22.04
4	28.65	71.01	0.10	0.11	0.13
5	30.78	68.84	0.12	0.11	0.15

tergranular phase (marked as "2" in Fig. 4(c)) and the matrix grains (marked as "1" in Fig. 4(c)) were shown in Fig. 4(d) and (e), respectively. EDS analysis shows the secondary phase at the grain boundary is rich in Cu, V, Bi and Zn (Fig. 4(d)), and those elements except Zn are not observed in matrix grains (Fig. 4(e)). The chemical compositions of the intergranular phase (marked as "2" and "3" in Fig. 4(c)) and the matrix grains (marked as "1", "4" and "5" in Fig. 4(c)) are listed in Table 1. Those results also demonstrate that the secondary phase contains five elements: Cu, V, Bi, Zn and O. furthermore, the content of Zn in secondary phase is higher than those of Cu, V and Bi, while the content of Zn in matrix grains deviate the stoichiometry of ZnNb₂O₆ and lower than the normal content according to the ratio of Zn/Nb = 1:2. These results suggest that Zn of ZnNb₂O₆ may be react with CuO, Bi₂O₃, V₂O₅ and form eutectic with liquid phase at high temperature and promote the sintering of ZnNb₂O₆ ceramics. The liquid phase then, re-crystallized during cooling [3] The melting point of the secondary phase and appearance temperature of liquid phase were not determined, However the melting point of ZnNb₂O₆, CuO, V₂O₅ and Bi₂O₃ are 1405, 1326, 690 and 825°C, respectively, and the high temperature melting test shows that the melting point of CuO-V₂O₅-Bi₂O₃ (the ratio is 1:1:1) is 780°C. Therefore, those results suggest that the liquid phase may be formed below 800°C.

Microwave dielectric properties of ZnNb₂O₆ ceramics with CuO-V₂O₅-Bi₂O₃ additives prepared under various temperatures were evaluated in order to clarify the effects of additions and sintering temperature on the microwave dielectric properties. Figure 5 shows the dielectric constant (ϵ_r) of ZnNb₂O₆ ceramics doped with CuO-V₂O₅-Bi₂O₃ as a function of sintering temperature. The ϵ_r values of samples increased with increasing sintering temperature and saturated at 850–900°C, then slightly decreased. These phenomena are attributed to

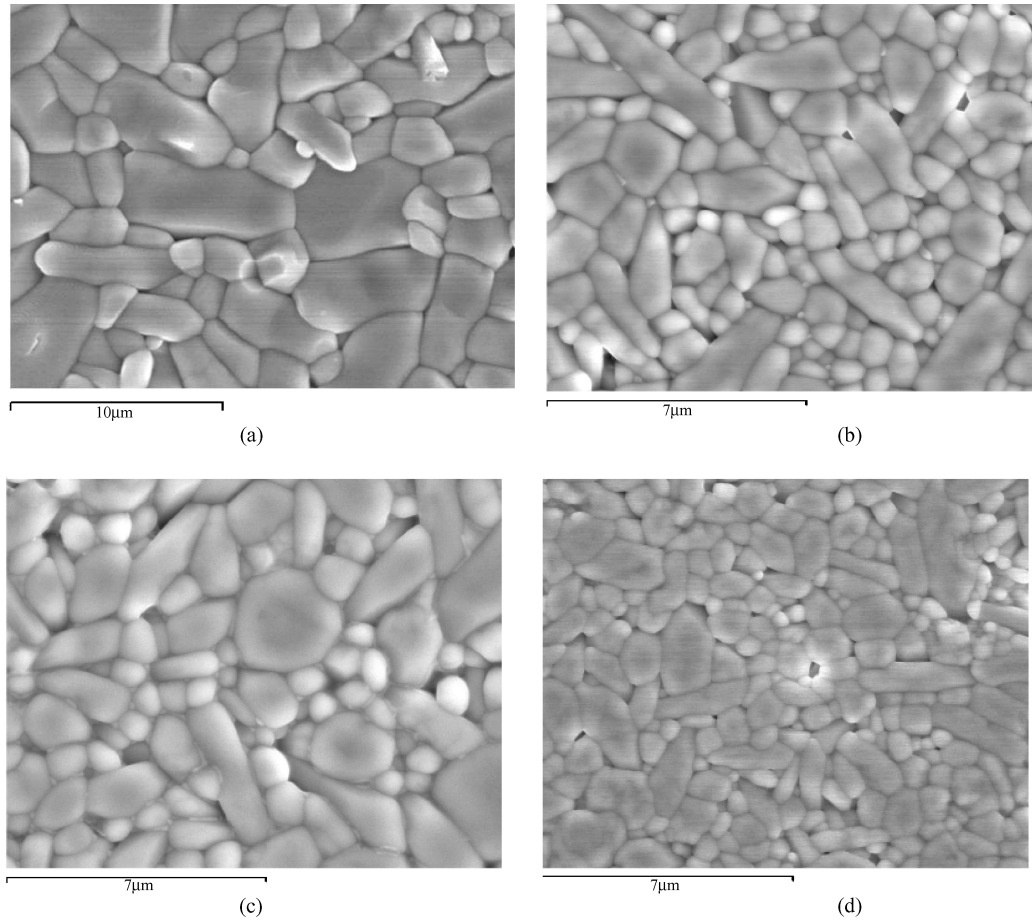


Fig. 3. SEM micrograph of polished and thermal etched ZnNb_2O_6 ceramics with 0.5 wt% CuO + 0.5 wt% V_2O_5 + (x) wt% Bi_2O_3 : (a) undoped ZnNb_2O_6 , 1150°C, (b) $x = 0.5$ wt%, 870°C, (c) $x = 2.0$ wt%, 870°C, (d) $x = 3.0$ wt%, 870°C.

the increase of relative density (D_r) which depends on the sintering temperature. On the other hand, the ε_r values of the ceramics also increased slightly with increasing amount of $\text{CuO-V}_2\text{O}_5\text{-Bi}_2\text{O}_3$ additions, and ranged from 22.61 to 24.17. The improvement of ε_r is closely related to the increase in relative density of ceramics at the same sintering temperature due to the increasing of sintering aids.

Figure 6 shows the quality factor ($Q \times f$) of ZnNb_2O_6 ceramics with $\text{CuO-V}_2\text{O}_5\text{-Bi}_2\text{O}_3$ additions as a function of sintering temperature. The $Q \times f$ values of ZnNb_2O_6 ceramics with different $\text{CuO-V}_2\text{O}_5\text{-Bi}_2\text{O}_3$ contents also increased with increasing sintering temperature, after reached the maximum values, then decreased. On the other hand, the $Q \times f$ values de-

creased with increasing amount of $\text{CuO-V}_2\text{O}_5\text{-Bi}_2\text{O}_3$ and changed from 67100 GHz (1.5 wt%) to 36118 GHz (4.0 wt%), moreover, all $Q \times f$ values of samples with $\text{CuO-V}_2\text{O}_5\text{-Bi}_2\text{O}_3$ additions are lower than that of undoped ZnNb_2O_6 ceramics sintered at 1150°C for 2 h. In general, microwave dielectric loss could be divided into two fields: the intrinsic loss and extrinsic loss. The intrinsic loss was mainly caused by lattice variation modes while the extrinsic loss was mainly dominated by secondary phase, oxygen vacancies, grains sizes and porosity [11]. In this study, the lower $Q \times f$ values for the ceramics with $\text{CuO-V}_2\text{O}_5\text{-Bi}_2\text{O}_3$ additions are considered to be caused by the crystal defect produced in crystal growth and the impurity effects of the secondary phase. In general, grain growth can improve

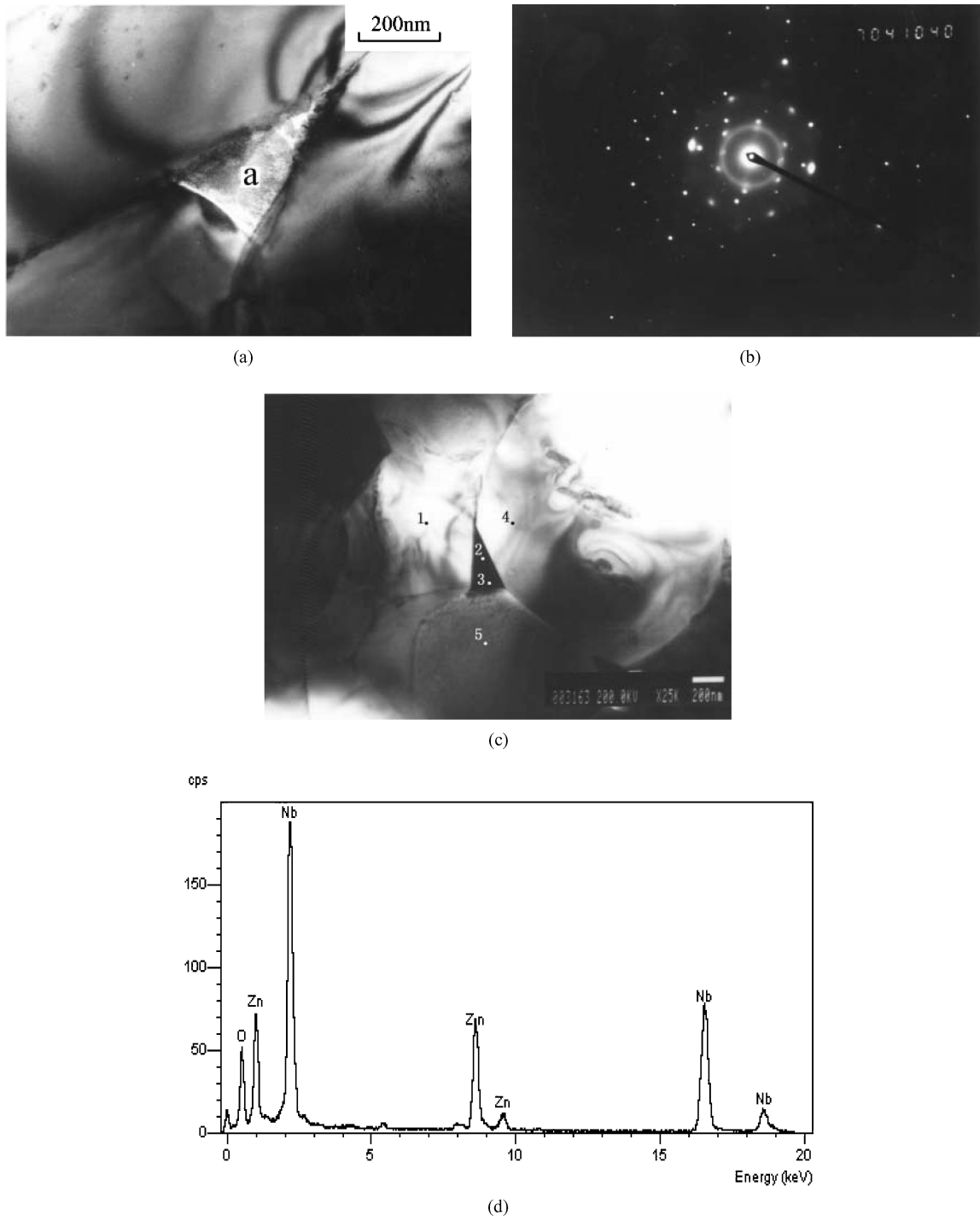


Fig. 4. TEM micrograph of ZnNb₂O₆ ceramics with (x) wt% CuO-Bi₂O₃-V₂O₅ additive sintered at 870°C. (a) Bright-field image, x = 4 wt% (b) SAD pattern of the intergranular phase marked as 'a' in (a), (c) Bright-field image, x = 1.5 wt%, (d) EDS graph of the intergranular phase marked as '2' in (c), (e) EDS graph of the matrix grains marked as '1' in (c). *(Continued on next page.)*

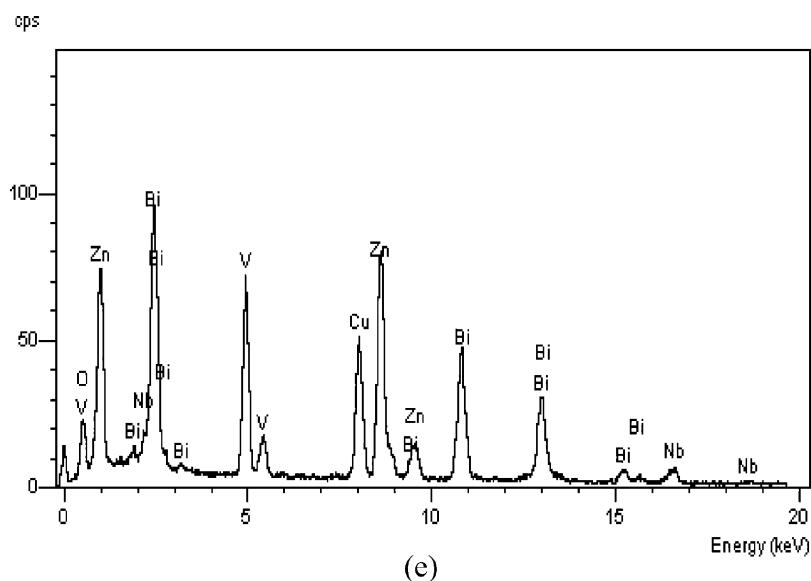
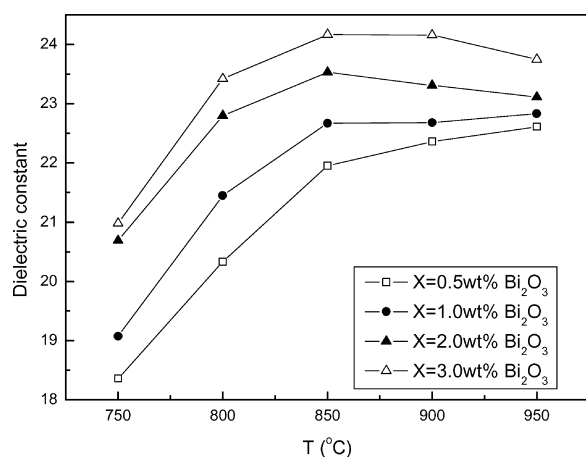
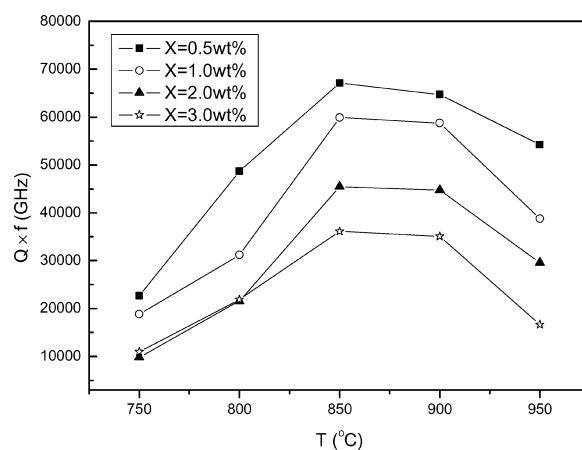


Fig. 4. (Continued).

Fig. 5. ϵ_r values of ZnNb_2O_6 ceramics doped with 0.5 wt% CuO + 0.5 wt% V_2O_5 + (x) wt% Bi_2O_3 additions as a function of sintering temperature.

the $Q \times f$ values, because as the grain size increased, the pores and grain boundary area decreased, which can reduce the lattice imperfections and increase the $Q \times f$ values [12, 13]. In this study, the average grain size is about $8 \mu\text{m}$ for undoped samples, the grain boundaries are very clear and no secondary phase observed, therefore, the $Q \times f$ value was very high for undoped sample, while the average grain size in major axis direction of ZnNb_2O_6 ceramics decreased from 6 to

Fig. 6. $Q \times f$ values of ZnNb_2O_6 ceramics doped with 0.5 wt% CuO + 0.5 wt% V_2O_5 + (x) wt% Bi_2O_3 additions as a function of sintering temperature.

$4 \mu\text{m}$ as the content of $\text{CuO-V}_2\text{O}_5\text{-Bi}_2\text{O}_3$ additions ranged from 1.5 to 4.0 wt% (Fig. 3(b) and (d)), and the $Q \times f$ values decreased from 67100 to 36118 GHz (Fig. 6). Those results suggest that too large an amount of $\text{CuO-V}_2\text{O}_5\text{-Bi}_2\text{O}_3$ addition inhibit the grain growth, and form a small grain in comparison with those of undoped sample or samples with small amount additives, which maybe decreased the $Q \times f$ values of ZnNb_2O_6 ceramics. On the other hand, the secondary

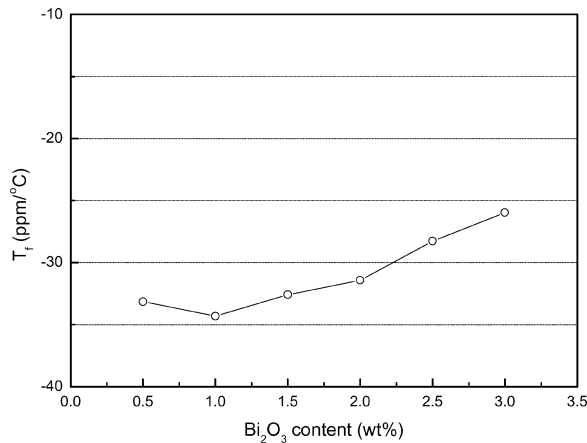


Fig. 7. τ_f values of ZnNb₂O₆ ceramics doped with 0.5 wt% CuO + 0.5 wt% V₂O₅ + (x) wt% Bi₂O₃ addition sintered at 870°C.

phase which is rich in Cu, V, Bi and Zn may bring the impurity to the ceramics, and thus anharmonicity in phonon vibration may increase with increasing of the secondary phase due to the adding of CuO-V₂O₅-Bi₂O₃ additions, which may cause the decrease of $Q \times f$ value.

Figure 7 shows the temperature coefficient of resonant frequency (τ_f) of ZnNb₂O₆ ceramics with different amount of CuO-V₂O₅-Bi₂O₃ additions sintered at 870°C. The τ_f values of samples shift to zero direction with increasing amount of CuO-V₂O₅-Bi₂O₃ additions. In general, τ_f value is known to be related with the tem-

perature coefficient of dielectric constant (τ_ϵ) and the thermal expansion coefficient (α_l) of which the value is approximately 10 ppm/°C in the microwave dielectric ceramics. And Lee et al. also reports that the τ_f values of MNb₂O₆ ceramics are considered to depend on the crystal structure on a basis of the relationship between τ_ϵ and unit cell volumes [3]. However, in the case of CuO-V₂O₅-Bi₂O₃-doped ZnNb₂O₆ ceramics, τ_f values may be primary influenced by the composition and content of the secondary phase if the crystal structure influence is ignored. The compositions of the secondary phase are very complex according to the results of XRD and EDS, there are no way to obtain the τ_f value of the secondary phase, therefore, it needs to be further studied for the secondary phase using other measure methods.

It is of interesting to investigate the co-fired behavior between the ZnNb₂O₆ ceramics and internal silver electrodes because ZnNb₂O₆ ceramics with CuO-V₂O₅-Bi₂O₃ additions shows good sintering properties below 900°C and excellent dielectric properties. Figure 8 shows SEM micrographs and EDS line scan of the interface between the ZnNb₂O₆ ceramics with CuO-V₂O₅-Bi₂O₃ additions and the silver electrode co-fired at 870°C for 2 h. SEM micrographs show that the silver internal electrodes were well formed and the reaction between the ZnNb₂O₆ ceramics and the silver electrode was not observed. Furthermore, EDS line scan also demonstrate this result. Therefore, low-firing ZnNb₂O₆ ceramics with CuO-V₂O₅-Bi₂O₃ additions

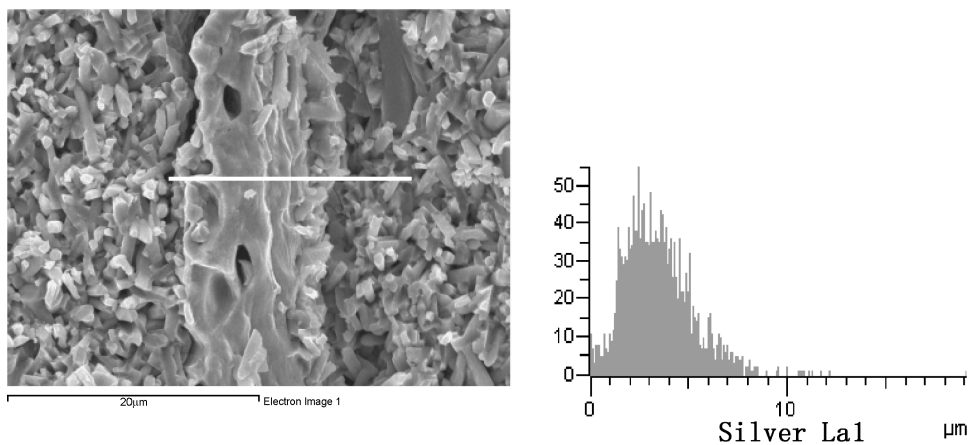


Fig. 8. SEM micrograph and EDS line scan of the interface between a silver electrode and the ceramic co-fired at 870°C.

are promising candidates for low-temperature sintering dielectrics applied in multilayer microwave devices.

Conclusions

The sintering temperature of ZnNb_2O_6 ceramics was significantly reduced from 1150 to 870°C by the co-doping of CuO, Bi_2O_3 and V_2O_5 . The secondary phase containing Cu, V, Bi and Zn were observed at grain boundary junction. The mechanism of low temperature sintering may be caused by that CuO, Bi_2O_3 , V_2O_5 and ZnNb_2O_6 forming a eutectic liquid phase (richen in Cu, V, Bi and Zn) at high temperature and promoting the sintering of ZnNb_2O_6 ceramics. The ZnNb_2O_6 ceramics doped with 1.5 wt% CuO- V_2O_5 - Bi_2O_3 additives exhibit excellent microwave dielectric properties: $\epsilon_r = 32.69$, $Q \times f = 67100$ GHz and $\tau_f = -32.69$ ppm/°C. CuO- V_2O_5 - Bi_2O_3 -doped ZnNb_2O_6 ceramics is chemically compatible with Ag electrode for multilayer microwave devices applications.

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